



New! UV-Vis/NIR Microscopic Spectrophotometer, MSV-5000 Series

By Kristen Burkhardt / April 24, 2012

JASCO introduced the MSV-5300 UV-Vis/NIR Microscope, one microscope system of the MSV-5000 series, during Pittcon 2012, Orlando, Florida. This microscope system incorporates a double-beam scanning spectrophotometer for optimum measurements in the UV-Vis to NIR region (200-2700 nm). The wide-band cassegrain objectives provide continuous transmittance/reflectance measurements for the entire spectral range desired, without the use of expensive, coated refractive objectives. An optional automated XYZ stage also offers mapping/imaging capability for larger samples.

The MSV-5000 series includes 3 different microscope systems; a dedicated UV-Vis microscope, the MSV-5100 (200-900 nm), the MSV-5200 which includes a Peltier-cooled PbS detector (200-2700 nm) and the MSV-5300, which incorporates an InGaAs detector to obtain optimized NIR measurements (200-1700 nm). All models incorporate a user-selectable slitwidth for variable spectral resolution as well as selectable circular apertures and an adjustable rectangular aperture for sample area discrimination. A PC-controlled objective carousel can be used to select any of the available 10X, 16X or 32X objectives in combination with the standard optical zoom feature to provide enhanced video imaging of the sample utilizing a high-resolution CMOS camera. Options include binocular viewing, polarized observation and selected refractive objective lenses.

For more information, visit the [MSV-5000](#) page.

About the Author

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